

Standard Test Method for Temperature Calibration on Cooling of Differential Scanning Calorimeters¹

This standard is issued under the fixed designation E 2069; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This test method covers the temperature calibration of differential scanning calorimeters on cooling using the difference between transition temperatures upon heating and cooling in the temperature range of 60 to 140 °C. An offset in the indicated temperature between heating and cooling experiments, within this temperature range, may be used to provide temperature calibration on cooling at other temperature ranges.

1.2 SI units are the standard.

1.3 This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to establish appropriate safety and health practices and determine the applicability of regulatory limitations prior to use. Specific precautionary statements are given in Section 6.

2. Referenced Documents

2.1 ASTM Standards:

- D 3418 Test Method for Transition Temperatures of Polymers by Thermal Analysis²
- E 473 Terminology Relating to Thermal Analysis³
- E 794 Test Method for Melting and Crystallization Temperatures by Thermal Analysis³
- E 928 Test Method for Determination of Purity by Differential Scanning Calorimetry³
- E 967 Practice for Temperature Calibration of Differential Scanning Calorimeters and Differential Thermal Analyzers³
- E 1970 Practice for Statistical Treatment of Thermoanalytical Data³

3. Terminology

3.1 Specific technical terms used in this test method are defined in Terminology E 473.

4. Summary of Test Method

4.1 The temperature sensor of the DSC, used to determine the temperature of a transition, is located close to but external

² Annual Book of ASTM Standards, Vol 08.02.

to the test specimen. This arrangement causes the indicated temperature to lead or lag the actual specimen temperature on heating/cooling causing the reported temperature to be higher on heating and lower on cooling than the actual specimen transition temperature. A DSC apparatus temperature, that has been calibrated for heating experiments, needs to be recalibrated for cooling experiments. Such a calibration on cooling is performed using a liquid crystal material, the transition(s) for which are not subject to super-heating or super-cooling.

4.2 The transition temperature of a rapid, non-superheating and non-supercooling transition is determined upon heating and upon cooling. The difference between these two indicated temperatures provides an offset temperature value between heating and cooling experiments at the indicated rate. This offset temperature value, when used with a precise temperature calibration upon heating, may serve as an instrument calibration function upon cooling.

5. Significance and Use

5.1 This test method is useful in calibrating the temperature signal of a differential scanning calorimeter for cooling experiments such as the determination of crystallization temperatures in Test Method D 3418 and Test Method E 794.

5.2 This test method may be used for research, development, analytical, specification acceptance, quality assurance and control purposes.

6. Precautions

6.1 Toxic or corrosive effluents, or both, may be released when heating the material of this test method and may be harmful to personnel and to the apparatus.

7. Apparatus

7.1 *Differential Scanning Calorimeter (DSC)*—The essential instrumentation required providing the minimum differential scanning calorimeter capability for this test method includes:

7.1.1 A DSC Test Chamber, composed of:

7.1.1.1 *A Furnace(s)*, to provide uniform controlled heating and cooling of a specimen and reference material to a constant temperature or at a constant rate within the applicable temperature range of this method.

7.1.1.2 A Temperature Sensor, that indicates specimen/

¹ This test method is under the jurisdiction of ASTM Committee E-37 on Thermal Measurements and is the direct responsibility of Subcommittee E37.01 on Test Methods and Recommended Practices.

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³ Annual Book of ASTM Standards, Vol 14.02.

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furnace temperature to ± 0.01 °C.

7.1.1.3 *A Differential Sensor*, to detect heat flow (power) difference between the specimen and reference equivalent to 10 μ W.

7.1.1.4 A means of sustaining a purge gas rate of 10 to 100 \pm 5 mL/min in the test chamber.

NOTE 1—Typically inert purge gases that inhibit specimen oxidation are 99 + % pure nitrogen, argon or helium. Subambient operation requires dry purge gases. Dry gases are recommended for all experiments unless the effect of moisture is part of the study.

7.1.2 A Temperature Controller, operating the furnace(s) between selected temperature limits, capable of controlling the rate of temperature change of 10 $^{\circ}$ C/min constant to

 \pm 0.1 °C/min or at an isothermal temperature constant to \pm 0.2 °C.

7.1.3 A Recording Device, digital or analog, capable of recording and displaying fractions of the heat flow signal (DSC curve), including the signal noise, on the Y-axis versus fractions of temperature signal, including the signal noise, on the X-axis.

7.1.4 *Containers*, (pans, crucibles, vials, etc. and lids) that are inert to the specimen and reference materials of suitable structural shape and integrity to contain the specimen and reference material.

7.1.5 *Cooling Capability*, at constant cooling rates of up to 10 °C/min in the temperature range of 140 to 60 °C, to hasten cool down from elevated temperatures, or to sustain an isothermal subambient temperature, or both.

7.2 *A Balance*, to weigh specimen and/or containers to ± 10 µg with a capacity of 100 mg or greater.

8. Calibration Materials

8.1 For the temperature range covered by many applications, the liquid crystal transitions of 99.8 to 99.9 % pure materials in Table 1 may be used for calibration. The calibrat-

TABLE 1 Transition Temperatures for Selected Liquid Crystal Calibration Materials

Liquid Crystal	Transition Type ^B	Transition Temperature, ^C	
Liquid Crystal Material ^A		K	°C
CE-3	$S_{C^*} \rightarrow Ch$	352.0	78.8
	$Ch \rightarrow I$	436.7	163.5
CE-8	$S_{J^*} \rightarrow S_{I^*}$	337.1	63.9
	$S_{I^*} \rightarrow S_{C^*}$	342.4	69.2
	$S_A \rightarrow Ch$	408.0	134.8
	$Ch \rightarrow I$	413.9	140.7
LC-1	$S_{C} \rightarrow N$	342.6	69.4
	$N \rightarrow I$	362.4	89.4

^ACE-3 = {(+)-4-n-hexyloxyphenyl 4'-(2"-methylbutyl)-biphenyl-4-carboxylate} CE-8 = {(+)-4(2'-methylbutyl)phenyl 4'-n-octylbiphenyl-4-carboxylate}

LC-1 = {N-(4-n-octyloxy-2-hydroxybenzal)4'-n-butylaniline}

 $^{B}Ch = Cholesteric$

Cr = Crystalline

I = Isotropic liquid

N = Nematic

 $S_A = Smectic A$

S_C= Smectic C

 S_{C^*} = Chiral smectic C

SI* = Smectic I*

 S_{J^*} = Smectic J*

 C The transition temperatures are dependent upon the purity of the liquid crystal material. These transition temperatures are those for 99.9 + mol % pure materials. See Footnotes 5, 6, and 7.

ing liquid crystal materials⁴ are known as CE-3 {(+)-4-nhexyloxyphenyl 4'-(2"-methylbutyl)-biphenyl-4carboxylate}(CAS no. 62614-61-3), CE-8 {(+)-4(2'methylbutyl)phenyl 4'-n-octylbiphenyl-4-carboxylate} and LC-1 {N-(4-n-octyloxy-2-hydroxybenzal)4'-n-butylaniline}.

NOTE 2—The purity of these liquid crystal materials may be determined by Test Method E 928 using the first liquid crystal transition prior to use (see Table 2).

9. Calibration

9.1 Perform any temperature calibration procedures recommended by the manufacturer of the differential scanning calorimeter as described in the operations manual.

9.2 Perform the temperature calibration of the differential scanning calorimeter using Practice E 967 and the heating rate of 10 $^{\circ}$ C/min. Indium is recommended as at least one of the calibration materials.

Note 3—For the purposes of this standard, temperature calibration on heating is performed at 10 $^{\circ}$ C/min and on cooling at 10 $^{\circ}$ C/min. Other rates for either heating or cooling may be used but shall be reported.

10. Procedure

10.1 Select a suitable calibrating liquid crystal material from Table 1.

Note 4—CE-3 and LC-1 may be used at all heating/cooling rates between 0.1 and 40 °C/min. CE-8 may be used for heating/cooling rates less than 10 °C/min.

10.2 Into a clean, tared specimen container weigh 3.0 to 5.0 mg of the liquid crystal calibration material.

NOTE 5—Larger specimen masses should not be used, as they will result in increased thermal lag effects.

10.3 Load the specimen into the test chamber, purge with dry nitrogen (or other inert purge gas) at the flow rate to be used for the subsequent application.

⁴ The sole source of supply of these materials known to the committee at this time is Chromophore, Inc., 2307 Spring Branch Road, Huntsville AL 35801. If you are aware of alternative suppliers, please provide this information to ASTM headquarters. Your comments will receive careful consideration at a meeting of the responsible technical committee, which you may attend.

 TABLE 2 Temperatures of the Crystal to First Liquid Crystal

 Transition of the Calibrating Materials

Liquid Crystal	Transition Tune ^B	Temperature, ^C	
Material ^A	Transition Type ^B	K	°C
CE-3	$Cr \rightarrow S_{C^*}$	339.2	66.0
CE-8	$Cr \to S_{J^\star}$	329.0	55.8
LC-1	$Cr \rightarrow S_C$	312.4	39.2

 ${}^{A}CE-3 = \{(+)-4-n-hexyloxyphenyl 4'-(2''-methylbutyl)-biphenyl-4-carboxylate\}$ CE-8 = $\{(+)-4(2'-methylbutyl)phenyl 4'-n-octylbiphenyl-4-carboxylate\}$

 $LC-1 = \{N-(4-n-octyloxy-2-hydroxybenzal)4'-n-butylaniline\}$

^BCh = Cholesteric

Cr = Crystalline

I = Isotropic liquid

N = Nematic

 $S_A = Smectic A$

S_c= Smectic C

 $S_{C^*}^-$ = Chiral smectic C

S_{I*}= Smectic I*

 S_{J^*} = Smectic J*

 C The transition temperatures are dependent upon the purity of the liquid crystal material. These transition temperatures are those for 99.9 + mol % pure materials. See Footnotes 5, 6, and 7.

10.4 Heat the specimen rapidly to 30 $^{\circ}$ C above the transition temperature to the isotropic phase as indicated in Table 1 and hold isothermally for 1 min.

Note 6—The transition temperature to the isotropic phase depends upon the calibration material selected and its purity.

10.5 Cool the specimen at 10 $^{\circ}$ C/min to 30 $^{\circ}$ C and hold isothermally for 1 min. Record the resultant thermal curve upon cooling (see Note 3).

Note 7—Liquid crystalline transitions are very narrow. Data collection rates of one data point every 0.05 °C (preferably every 0.01 °C) shall be used to achieve the precision required.

10.6 Heat the specimen at 10 $^{\circ}$ C/min to 30 $^{\circ}$ C above the temperature of the transition to the isotropic phase as indicated in Table 1. Record the resulting thermal curve upon heating (see Note 3).

10.7 From the resultant thermal curve upon cooling from 10.5, determine the extrapolated onset temperature (T_c) to \pm 0.01 °C for each liquid crystal \rightarrow liquid crystal or each liquid crystal \rightarrow isotropic transition in Table 1 observed as illustrated in Fig. 1.

Note 8—Use only a transition where the signal returns to baseline before the transition onset.

NOTE 9—Retain all available significant figures for these calculations and round to the final result to the number of significant figures described in section 13

10.8 From the resultant thermal curve upon heating from 10.6, determine the extrapolated onset temperature (T_b) to \pm

0.01 °C for each liquid crystal \rightarrow liquid crystal or each isotropic \rightarrow liquid crystal transition in Table 1 observed as illustrated in Fig. 2 (see Note 8).

10.9 Calculate the offset temperature (ΔT) for each liquid crystal transition to \pm 0.01 °C according to 11.1.

11. Calculation

11.1 Calculate the offset temperature (ΔT) to \pm 0.01 °C for each transition according to Eq 1:

$$\Delta T = T_h - T_c \tag{1}$$

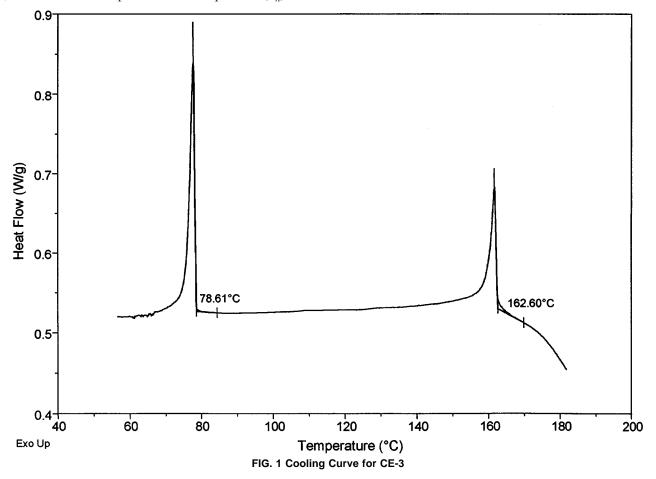
where:

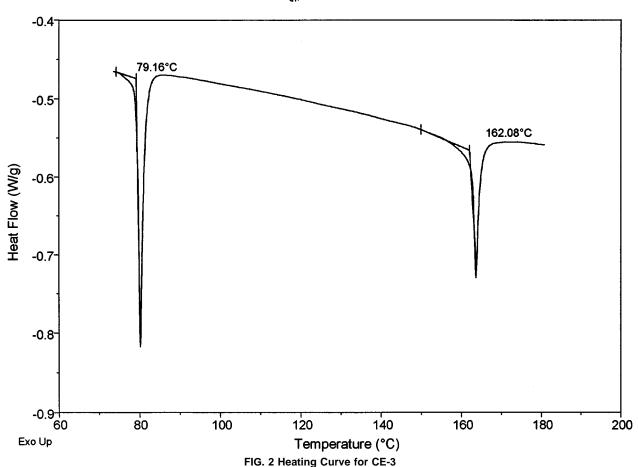
- T_h = the transition temperature of a specific liquid crystal transition observed on heating,
- T_c = the temperature of the same transition measured on cooling, and
- ΔT = the offset temperature for the specific liquid crystal transition.

11.2 If more than one transition is observed, calculate and report the individual offset temperatures, and the mean value of all offset temperatures (see Practice E 1970).

11.3 In an application cooling experiment, where the differential scanning calorimeter has been calibrated upon heating, the temperature of a cooling transition within or without the 60 to 140 °C temperature range may be determined using Eq 2:

$$T_x = T_o + \Delta T \tag{2}$$





where:

- T_x = the temperature of the unknown transition upon cooling,
- T_{a} = the observed temperature upon cooling, and
- ΔT = the offset temperature determined for the specific heating rate-cooling rate combination determined in this test method.

12. Report

12.1 Report the following information:

12.1.1 Description of the differential scanning calorimeter used for the test including model and serial number,

12.1.2 Complete identification and description of the reference materials and their transitions used including source, method or purification (if any) and purity,

12.1.3 Statement of the mass, dimensions geometry, and material of the specimen, material of the specimen container and temperature program rate on heating and cooling,

12.1.4 Identification of the specimen atmosphere by purge gas composition, purity and flow rate,

12.1.5 Results of the calibration procedure including the value of the offset temperature (ΔT) term, and

12.1.6 The specific dated version of the standard used.

13. Precision and Bias

13.1 An interlaboratory test is planned for during 2000 to determine the precision and bias of this test method. Anyone wishing to participate in this interlaboratory test may contact the E 37 Staff Manager at ASTM Headquarters.

13.2 Ruggedness testing^{5,6,7} indicates that the value for ΔT and its precision depends upon the instrument type being used. 13.3 *Precision*:

13.3.1 Testing in a single laboratory⁶ indicates that, for power compensation differential scanning calorimeters, the precision of the measured ΔT is independent of heating/cooling rates. The standard deviation for ΔT is ± 0.29 °C.

13.3.2 Testing in a single laboratory⁷ indicates that, for heat flux differential scanning calorimeters, the precision of the measured ΔT is dependent on heating/cooling rate. The coefficient of variation for ΔT is 0.27.

13.3.3 Testing in two laboratories^{6,7} using instruments of differing operating principles, indicates that the precision for the measured ΔT depends upon its value. At heating/cooling rates of 10 (and -10) °C/min, the pooled standard deviation is 0.25 °C.

13.4 Bias:

13.4.1 Testing in a single laboratory⁶ indicates, that for power compensation differential scanning calorimeters, the value for ΔT ranges from 1.7 to -0.2° C when the heating (and cooling) rate ranges from 20 (and -20) to 2 (and -2) °C/min.

13.4.2 Testing in a single laboratory⁷ indicates that, for heat flux differential scanning calorimeters, the value of ΔT ranges from 1.7 to 0.2 °C when heating/cooling rate ranges from 20

⁵ Menczel, J.D., Leslie, T.M.; *Thermochim. Acta*, 166, 1990, 309–317.

⁶ Menczel, J.D., Leslie, T.M., J. Therm. Anal., 40, 1993, 957–960.

⁷ Menczel, J.D.,; J. Therm Anal., 49, 1997, 193–199.

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(and -20) to 2 (and -2) °C/min.

14. Keywords

13.4.3 Testing in two laboratories^{6,7} using instruments of different operating principles indicates that the value for ΔT ranges from 1.7 to -0.2 °C when the heating (and cooling) rate ranges from 20 (and-20) to 2 (and -2) °C/min.

14.1 calibration; differential scanning calorimetry; temperature; thermal analysis

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